

**Notice of References Cited**

Application/Control No.

10/526,115

Applicant(s)/Patent Under  
Reexamination  
KAARIO ET AL.

Examiner

Van Kim T. Nguyen

Art Unit

2152

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,258,276	08-2007	Linton et al.	235/385
*	B	US-7,229,021	06-2007	Vesikivi et al.	235/462.01
*	C	US-7,175,093	02-2007	Bridgelall, Raj	235/472.01
*	D	US-7,020,685	03-2006	Chen et al.	709/204
*	E	US-6,989,750	01-2006	Shanks et al.	340/572.4
*	F	US-6,928,486	08-2005	Ono, Hiroshi	709/246
*	G	US-6,843,415	01-2005	Vogler, Hartmut K.	235/385
*	H	US-6,563,417	05-2003	Shaw, David A.	340/10.1
*	I	US-5,864,765	01-1999	Barvesten, Mats O.	455/565
*	J	US-2003/0095032	05-2003	Hoshino et al.	340/5.92
*	K	US-2002/0116268	08-2002	Fukuda, Kunio	705/14
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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